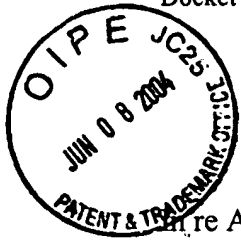


IFW

Docket No.: 87333.2462

PATENT/OFFICIAL



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Entire Application of

Hermann STAHL, et al.

Serial No. 10/774,410

Filed: February 10, 2004

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: Group Art Unit: 2878  
:  
: Examiner:

For: MEASURING DEVICE FOR DETERMINING THE CONCENTRATION OF GASES  
BY INFRARED ABSORPTION

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

No further elaboration is believed necessary. Copies of the documents are submitted herewith in accordance with 37 C.F.R. §1.98(a).

AUTHORIZATION

This Information Disclosure Statement is being filed before receipt of the first Office Action. No fee is required. The Commissioner is hereby authorized to charge any additional fees which may be required for this submission, or credit any overpayment to deposit account no. 50-2036.

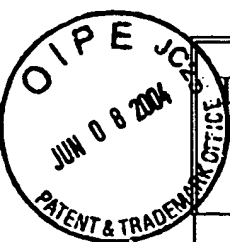
Respectfully submitted,

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LIST OF ART CITED BY APPLICANT (PTO-1449)					ATTY. DOCKET NO. 87333.2462	SERIAL NO. 10/774,410	
					APPLICANT Hermann STAHL, et al.		
					FILING DATE 2/10/04		GROUP 2878
U.S. PATENT DOCUMENTS							
	EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
A		5,923,035	7/13/99	Tobias Winkler, et al.	250	338.5	8/21/97
B							
C							
D							
E							
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FOREIGN PATENT DOCUMENTS							
	EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
U							
V							
W							
X							
Y							
Z							
AA							
BB							
CC							
DD							
EE							
FF							
GG							
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
HH							
II							
JJ							
KK							
LL							
MM							
NN							
EXAMINER					DATE CONSIDERED		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.